

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.	:	10/622,933	Confirmation No: 3481
Applicant	:	Chee Hong Liau	
Filed	:	July 18, 2003	
Title	:	Method of Processing Test Patterns for an Integrated Circuit	
Art Unit	:	2128	
Examiner	:	Saif A. Alhija	
Docket No.	:	M&N-IT-465	
Customer No.	:	24131	

AMENDMENT

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Responsive to the Office action dated October 3, 2006 kindly amend the above-identified application as follows:

- **Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.
- **Remarks/Arguments** begin on page 9 of this paper.